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SEMICONDUCTOR

74FR900 9-Bit, 3-Port Latchable Datapath Multiplexer

General Description

The 74FR900 is a data bus multiplexer routing any of three 9-bit ports to any other one of the three ports. Readback of data latched from any port onto itself is also possible. The 74FR900 maintains separate control of all latch-enable, output enable and select inputs for maximum flexibility. PINV allows inversion of the data from the C_8 to A_8 or B_8 path. This is useful for control of the parity bit in systems diagnostics.

Fairchild's 74FR25900 includes 25Ω resistors in series with port A and B outputs. Resistors minimize undershoot and ringing which may damage or corrupt sensitive device inputs driven by these ports.

Features

- 9-bit data ports for systems carrying parity bits
- Readback capability for system self checks.
- Independent control lines for maximum flexibility
- Guaranteed multiple output switching and 250 pF load delavs

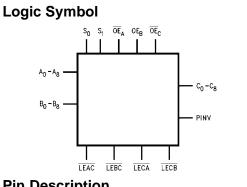
May 1992

Revised August 1999

- Outputs optimized for dynamic bus drive capability
- PINV parity control facilitates system diagnostics
- FR25900 resistor option for driving MOS inputs such as DRAM arrays

Ordering Code:

Order Number	Package Number	Package Description
74FR900SSC	MS48A	48-Lead Small Shrink Outline Package (SSOP), JEDEC MO-118, 0.300 Wide
Devices also available	in Tape and Reel Specify	y by appending the suffix letter "X" to the ordering code



Pin Description

Pin Names	Description
LExx	Latch Enable Inputs
OEx	Output Enable Inputs
PINV	Parity Invert Input
S ₀ , S ₁	Select Inputs
A ₀ -A ₈	Port A Inputs or 3-STATE Outputs
B ₀ -B ₈	Port B Inputs or 3-STATE Outputs
C ₀ –C ₈	Port C Inputs or 3-STATE Outputs

Connection Diagram

S₀ GND A₈ Α7

A₁ Ao PINV ŌĒĄ

LECA

$ \begin{array}{cccccccccccccccccccccccccccccccccccc$		agram		
$\begin{array}{cccccccccccccccccccccccccccccccccccc$		\bigcirc		
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	с ₄ —	1	48	- v _{cc}
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	GND -	2	47	— c ₅
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	с ₃ —	3	46	
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	c ₂ —	4	45	
		5	44	— с ₈
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	с _о —	6	43	
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$		7	42	- OE _C
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	s ₀ —	8	41	OEB
$\begin{array}{cccccccccccccccccccccccccccccccccccc$		9	40	– v _{cc}
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	A ₈ —	10	39	— в _о
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	A7 -	11	38	
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	A ₆ —	12	37	— в ₂
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	A5 —	13	36	
$\begin{array}{cccccccccccccccccccccccccccccccccccc$		14	35	
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$		15	34	— B ₄
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$		16	33	
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	A3 -	17	32	— B ₅
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	A2 -	18	31	— в ₆
$\begin{array}{c c} PINV &= 21 & & 28 & - \overline{LECB} \\ \hline \overline{OE}_{A} &= 22 & & 27 & - \overline{LEBC} \\ V_{CC} &= 23 & & 26 & - \overline{LEAC} \end{array}$		19	30	
$\begin{array}{c c} PINV &= 21 & & 28 & - \overline{LECB} \\ \hline \overline{OE}_{A} &= 22 & & 27 & - \overline{LEBC} \\ V_{CC} &= 23 & & 26 & - \overline{LEAC} \end{array}$	A ₀ —	20	29	— в ₈
V _{CC} - 23 26 - LEAC		21	28	
V _{CC} - 23 26 - LEAC	OE _A -	22	27	LEBC
		23	26	LEAC
		24	25	- GND
	l			I

Functional Description

The 74FR900 allows 9-bit data to be transferred from any of three 9-bit I/O ports to either of the two remaining I/O ports. The device employs latches in all paths for either transparent or synchronous operation. Readback capability from any port to itself is also possible.

Data transfer within the 74FR900 is controlled through use of the select (S₀ and S₁) and output-enable (\overline{OE}_A, OE_B and \overline{OE}_C) inputs as described in Table 1. Additional control is available by use of the latch-enable inputs ($\overline{LEAC}, LECA, LEBC, LECB$) allowing either synchronous or transparent transfers (see Table 2). Table 1 indicates several readback conditions. By latching data on a given port and initiating the readback control configuration, previous data may be read for system verification or diagnostics. This mode may be useful in implementing system diagnostics.

Data at the port to be readback must be latched prior to enabling the outputs on that port. If this is not done, a closed data loop will result causing possible data integrity problems. Note that the A and B ports allow readback without affecting any other port. Port C, however, requires interruption of either port A or B to complete its readback path.

PINV controls inversion of the C₈ bit. A low on PINV allows C₈ data to pass unaltered. A high causes inversion of the data. See Table 3. This feature allows forcing of parity errors for use in system diagnostics. This is particularly helpful in 486 processor designs as the 486 does not provide odd/even parity selection internally.

		Inputs			
S ₀	S ₁	OEA	OEB	OEC	Function
L	Х	Н	L	L	Port A to Port C
L	L	н	н	н	Port A to Port B
L	0	Н	н	L	Port A to B+C
Н	L	L	L	н	Port B to Port A
Н	Х	Н	L	L	Port B to Port C
н	0	L	L	L	Port B to A+C
Х	н	L	L	н	Port C to Port A
Х	Н	Н	н	н	Port C to Port B
Х	Н	L	н	н	Port C to A+B
Х	Х	н	L	н	Outputs Disabled
L	L	L	Х	Х	(Readback to A) (Note 1)
L	Н	L	Х	L	(Readback to A or C) (Note 1)
н	L	х	Н	х	(Readback to B) (Note 1)
н	н	Х	Н	L	(Readback to B or C) (Note 1)

TABLE 1. Datapath Control

Note 1: Readback operation in latched mode only. Transparent operation could result in unpredictable results.

TABLE 2. Latch-Enable Control

H = HIGH Voltage Level

LExx	Input	Output
L	L	L
L	н	н
Н	Х	Q ₀

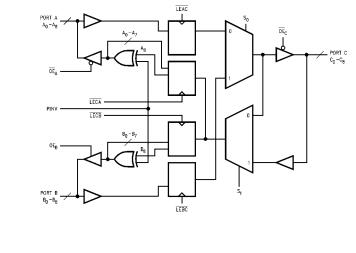
L = LOW Voltage

TABLE 3. PINV Control

PINV	C ₈	A ₈ or B ₈
L	L	L
L	н	н
н	L	н
н	н	L

Q₀ = Output state prior to LExx LOW-to-HIGH transition

Logic Diagram



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Absolute Maximum Ratings(Note 2)

Storage Temperature	$-65^{\circ}C$ to $+150^{\circ}C$
Ambient Temperature under Bias	$-55^{\circ}C$ to $+125^{\circ}C$
Junction Temperature under Bias	-55°C to +150°C
V _{CC} Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 3)	-0.5V to +7.0V
Input Current (Note 3)	-30 mA to +5.0 mA
Voltage Applied to Output	
in HIGH State (with $V_{CC} = 0V$)	
Standard Output	–0.5V to V _{CC}
3-STATE Output	-0.5V to +5.5V
Current Applied to Output	
in LOW State (Max)	twice the rated I _{OL} (mA)
ESD Last Passing Voltage (Min)	4000V

Recommended Operating Conditions

Free Air Ambient Temperature Supply Voltage 74FR900

0°C to +70°C +4.5V to +5.5V

Note 2: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 3: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

Symbol	Parameter	Min	Тур	Max	Units	V _{cc}	Conditions
V _{IH}	Input HIGH Voltage	2.0			V		Recognized HIGH Signal
V _{IL}	Input LOW Voltage			0.8	V		Recognized LOW Signal
V _{CD}	Input Clamp Diode Voltage			-1.2	V	Min	I _{IN} = -18 mA
V _{OH}	Output HIGH Voltage	2.4			V	Min	$I_{OH} = -3 \text{ mA} (A_n, B_n, C_n)$
		2.0			V	Min	$I_{OH} = -15 \text{ mA} (A_n, B_n, C_n)$
V _{OL}	Output LOW Voltage			0.50	V	Min	$I_{OL} = 24 \text{ mA} (A_n, B_n, C_n)$
IIH	Input HIGH Current			5	μA	Max	V _{IN} = 2.7V (Control Inputs)
I _{BVI}	Input HIGH Current Breakdown Test			7	μΑ	Max	V _{IN} = 7.0V (Control Inputs)
I _{BVIT}	Input HIGH Current Breakdown Test (I/O)			100	μΑ	Max	$V_{IN} = 5.5V (A_n, B_n, C_n)$
IIL	Input LOW Current			-150	μΑ	Max	V _{IN} = 0.5V (Control Inputs)
V _{ID}	Input Leakage Test	4.75			v	0.0	I _{ID} = 1.9 μA, All Other Pins Grounded
I _{OD}	Output Circuit Leakage Test			3.75	V	0.0	V _{IOD} = 150 mV, All Other Pins Grounded
I _{IH} + I _{OZH}	Output Leakage Current			25	μA	Max	V _{OUT} =2.7V (A _n , B _n , C _n)
$I_{IIL} + I_{OZL}$	Output Leakage Current			-150	μΑ	Max	$V_{OUT} = 0.5V (A_n, B_n, C_n)$
I _{OS}	Output Short Circuit Current	-100		-225	mA	Max	$V_{OUT} = 0.0V (A_n, B_n, C_n)$
I _{CEX}	Output HIGH Leakage Current			50	μΑ	Max	$V_{OUT} = V_{CC} (A_n, B_n, C_n)$
I _{ZZ}	Bus Drainage Test			100	μA	0.0	$V_{OUT} = 5.25V (A_n, B_n, C_n)$
I _{CCH}	Power Supply Current		115	150	mA	Max	All Outputs HIGH (Note 4)
I _{CCL}	Power Supply Current		170	200	mA	Max	All Outputs LOW (Note 4)
I _{CCZ}	Power Supply Current		147	175	mA	Max	Outputs in 3-STATE

Note 4: 2 ports active only

			$T_A = +25^{\circ}C$		$T_A = 0^\circ C$	to +70°C	
Cumb al	Parameter		V _{CC} = +5.0V	1	V _{CC} =	+5.0V	Units
Symbol	Parameter		$C_L = 50 \ pF$		C _L =	50 pF	Units
		Min	Тур	Max	Min	Max	-
t _{PLH}	Propagation Delay						
t _{PHL}	A _n or B _n to C _n	2.0	4.2	7.0	2.0	7.0	ns
	C _n to A _n or B _n						
t _{PLH}	Propagation Delay	2.5	4.8	7.5	2.5	7.5	ns
t _{PHL}	C ₈ to A ₈ or B ₈ (PINV HIGH)	2.0	4.0	1.5	2.0	1.5	ns
t _{PLH}	Propagation Delay	4.5	6.4	10.0	4.5	10.0	ns
t _{PHL}	A _n to B _n , B _n to A _n	4.0					
t _{PLH}	Propagation Delay	4.5	6.8	10.0	4.5	10.0	ns
t _{PHL}	LEAC to C_n , LEBC to C_n	4.0	0.0	10.0	4.5		
t _{PLH}	Propagation Delay	3.0	6.0	9.5	3.0	9.5	ns
t _{PHL}	$\overline{\text{LECA}}$ to A _n , $\overline{\text{LECB}}$ to B _n		0.0	9.5			
t _{PLH}	Propagation Delay	3.0	6.0	10.0	3.0	10.0	ns
t _{PHL}	S ₀ to C _n	3.0	0.0	10.0	3.0	10.0	115
t _{PLH}	Propagation Delay	3.5	6.5	11.0	3.5	11.0	ns
t _{PHL}	S ₁ to A _n or B _n	5.5	0.5	11.0	5.5	11.0	115
t _{PLH}	Propagation Delay	2.0	5.0	9.0	2.0	9.0	ns
t _{PHL}	PINV to A ₈ or B ₈	2.0	0.0	3.0	2.0	3.0	115
t _{PZH}	Output Enable Time	2.0	4.0	6.5	2.0	6.5	ns
t _{PZL}	A _n , C _n	2.0	4.0	0.0	2.0	0.0	113
t _{PHZ}	Output Disable Time	1.5	4.0	6.0	1.5	6.0	ns
t _{PLZ}	A _n , C _n	1.5	4.0	0.0	1.0	0.0	113
t _{PZH}	Output Enable Time	2.0	5.0	7.0	2.0	7.0	ns
t _{PZL}	B _n	2.0	5.0		2.0		113
t _{PHZ}	Output Disable Time	2.0	5.0	7.0	2.0	7.0	ns
t _{PLZ}	B _n	2.0	0.0	7.0	2.0	7.0	113

AC Operating Requirements

Symbol			$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$T_{A} = 0^{\circ}C \text{ to } +70^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$	
		Min	Тур	Max	Min	Max	
t _S (H)	Setup Time, HIGH or LOW	4.0	2.0		4.0		ns
t _S (L)	A_n to LEAC, B_n to LEBC	4.0	2.0		4.0		115
t _H (H)	Hold Time, HIGH or LOW	1.0	2.0		1.0		
t _H (L)	A_n to LEAC, B_n to LEBC	1.0	-2.0		1.0		ns
t _S (H)	Setup Time, HIGH or LOW	2.0	1.0		2.0		
t _S (L)	C _n to LECA or LECB	3.0	1.0		3.0		ns
t _H (H)	Hold Time, HIGH or LOW	1.0	1.0		1.0		
t _H (L)	C _n to LECA or LECB	1.0	-1.0		1.0		ns
t _W (H)	LE Pulse Width LOW	8.0	4.0		8.0		ns

Extended AC Electrical Characteristics

	$T_A = 0^\circ C$	to +70°C	$T_A = 0^\circ C$			
	$V_{CC} = +5.0V$		$V_{CC} = +5.0V$			
Symbol	Symbol Parameter	C _L = 50 pF		C _L = 250 pF		Units
	Nine Outputs Switching		(Note 6)			
		(No	te 5)			
		Min	Max	Min	Max	
t _{PLH}	Propagation Delay					

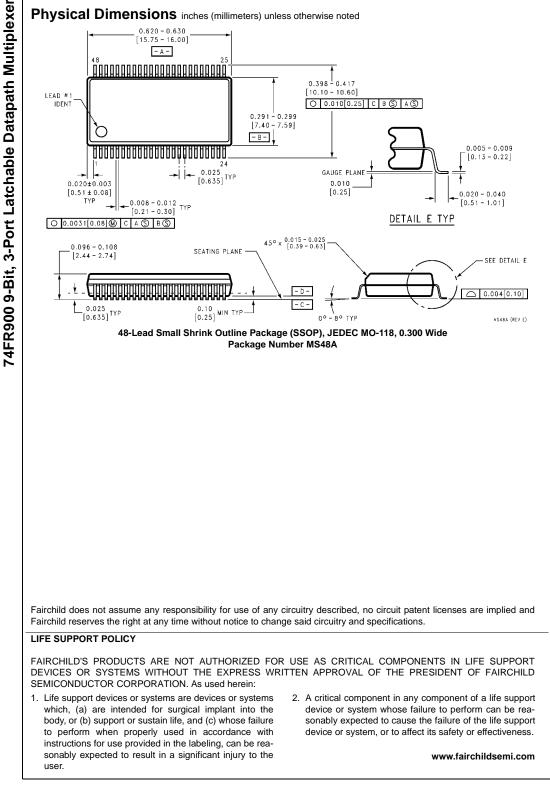
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Symbol	Parameter	$T_{A} = 0^{\circ}C$ $V_{CC} =$ $C_{L} =$ Nine Output (Not	T _A = 0°C V _{CC} = C _L = 2 (No	Units		
		Min	Max	Min	Max	
t _{PHL}	A _n or B _n to C _n	2.0	9.0	2.5	10.5	ns
	C _n to A _n or B _n					
t _{PLH}	Propagation Delay			3.5	11.0	ns
t _{PHL}	C ₈ to A ₈ or B ₈ (PINV HIGH)			0.0		
t _{PLH}	Propagation Delay	4.5	12.0	5.5	13.5	ns
t _{PHL}	A _n to B _n , B _n to A _n		.2.0	0.0	10.0	
t _{PLH}	Propagation Delay	4.5	12.0	5.5	13.5	ns
t _{PHL}	LEAC to C _n , LEBC to C _n		12.0	0.0	10.0	
t _{PLH}	Propagation Delay	3.0	11.5	4.0	13.5	ns
t _{PHL}	LECA to A _n , LECB to B _n	5.0	11.5	4.0	15.5	115
t _{PLH}	Propagation Delay	3.0	11.0	3.0	14.0	ns
t _{PHL}	S ₀ to C _n	5.0	11.0	5.0	14.0	115
t _{PLH}	Propagation Delay	3.5	12.0	4.5	15.0	ns
t _{PHL}	S ₁ to A _n or B _n	3.5	12.0	7.5	10.0	115
t _{PLH}	Propagation Delay			2.5	12.0	ns
t _{PHL}	PINV to A ₈ or B ₈			2.5	12.0	115
t _{PZH}	Output Enable Time	2.0	8.0			ns
t _{PZL}	A _n , C _n	2.0	0.0			113
t _{PHZ}	Output Disable Time	1.5	6.0			ns
t _{PLZ}	A _n , C _n	1.0	0.0			
t _{PZH}	Output Enable Time	2.0	8.0			ns
t _{PZL}	B _n	2.0	0.0			
t _{PHZ}	Output Disable Time	2.0	7.0			ns
t _{PLZ}	Bn	2.0				

Note 5: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase, i.e., all LOW-to-HIGH, HIGH-to-LOW, 3-STATE-to-HIGH, etc.

Note 6: This specification is guaranteed but not tested. The limits represent propagation delays with 250 pF load capacitors in place of the 50 pF load capacitors standard AC load. This specification pertains to single output switching only.

74FR900



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